

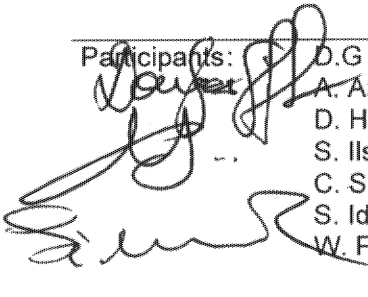


SPIRE-AST-MOM-002466

Minutes of Meeting

Date:	19.07.2005	Herschel	
Doc.-No.:	HP-2-ASED-MN-1018		
Meeting place:	EADS Astrium OTN	Chairman:	S. Idler
Date/Time:	19.07.2005 / 14:00	Secretary	S. Idler
Agenda dated:	PTR Standard Agenda	Close of Meeting:	19.07.2005

Subject: SPIRE SIH Electrical Integration PTR

Participants: 	D.G. riffin	SPIRE	Additional Distribution:	ESA
	A. Aramburu	SPIRE		ASP
	D. Hendry	ASED		
	S. Ilsen	ASED		
	C. Schlosser	ASED		
	S. Idler	ASED		
	W. Pinter-Krainer	ESA		

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<input type="checkbox"/> Brief-Minutes (except following sheets)	<input type="checkbox"/> Summary of Results of Sheets 2 till
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Summary and Conclusion:

SIH mating and the instrument warm functional test after mating have been successfully performed. The functioning of the integrated SIH together with the instrument has been successfully validated as far as possible with FPU warm. 2 NCR's have been raised which do not block the closure of the CVV.



Reference	Results	Remarks
	<p>PTR Agenda:</p> <ol style="list-style-type: none">1. Identification of Test Item2. Review of Manufacturing, Integration & Test Doc.3. Review of Test Data / Reports / Procedure Variation Sheets4. NCR / RFW Review5. Open Work / Open Actions Identification6. Conclusion on Post Test Review (PTR)	



Reference	Results	Remarks
	<p>1. Identification of Test Item</p> <p>See TRR minutes HP-2-ASED-MN-1012, section 1 and 2. After SIH mating to the SPIRE instrument the functional test has been performed. No changes to software configuration since TRR.</p> <p>2. Review of Manufacturing, Integration & Test Doc.</p> <p>Integration and test procedures as per TRR minutes HP-2-ASED-MN-1012. Procedure "Warm Functional Test after Electrical Integration" SPIRE-RAL-PRC-002422 has been updated to issue 1.4. Procedure variations are listed in the test report (see below).</p> <p>3. Review of Test Data / Reports / Procedure Variation Sheets</p> <p>The following reports have been generated:</p> <ul style="list-style-type: none"> • SIH mating report: under preparation by SPIRE. • Report for Warm Functional Test after Electrical Integration: HP-2-ASED-TR-0077. • Data analysis report from SPIRE: under preparation by SPIRE. <p>No additional reports. No tests to be repeated.</p> <p>Procedure variation sheets are part of the test reports.</p>	



Reference	Results	Remarks
	<p>3. NCR / RFW Review</p> <p>Existing NCR's see TRR minutes HP-2-ASED-MN-1012. None of these have been closed during that test.</p> <p>The following new NCR's have been raised during the mating/test:</p> <p><u>ASED-NC-1269: tmd.dat file not complete</u> Alcatel should add all missing SPIRE SPID's to the tmd.dat file and provide a new MIB. NCR open.</p> <p><u>ASED-NC-1270: CCS packet display problems</u> The CCS window "Packet History Display" shows gaps in the sequence of packets. Problem seems to be within CCS software. To be investigated by Alcatel/Terma. NCR open.</p> <p>The new NCR's are attached to the report HP-2-ASED-TR-0077.</p> <p>The following problems were observed resulting from existing NCR's:</p> <p><u>Loose JFET connectors</u> During SPIRE SIH mating to the JFET MDM connectors, it was observed that with the securing screws fully tightened the harness connector can still move. The connectors are as follows: MDM 37 pin connectors HSJFS 121220 P9 and P10 HSJFP 121210 P25, 26, 27, 28 MDM 25 pin connectors HSJFS 121220 P05 and P06</p>	



Reference	Results	Remarks
	<p>HSJFP 121210 P13,14,15,16 It appears that the screws are too long and bottom out. The FPU connectors have been checked and are ok. For EQM the disposition is "use as is" as the connectors are fully mated and there is no gap but there is slight rotational movement. This situation could be a result of NCR ASED-NC-0686. To be checked for PFM.</p> <p><u>Automatic switch-on procedure does not work</u> Problem related to ASED-NCR-0251 (First command has to be sent twice) have occurred. Switch-on had to be made manually. NCR to be resolved by Alcatel since it considerably hampers the testing.</p> <p>5. Open Work / Open Actions Identification</p> <p>The following work has to be done prior to closure of the CVV:</p> <ol style="list-style-type: none"> 1. Fix copper tape with conductive glue / Kapton tape on open JFET connectors (EMI protection). 2. Clearance between SPIRE level 3 straps and OBA is very close. Take photos and measure gap with feeler gauge. ASED thermal engineer to review. <p>6. Conclusion on Post Test Review (PTR)</p> <p>SIH mating and the instrument warm functional test after mating have been successfully performed. The functioning of the integrated SIH together with the instrument has been validated as far as possible with FPU warm. 2 NCR's have been raised which do not block the closure of the CVV.</p>	

